

phase and exsolution in the triple point and distribution concerted on the pores. The dielectric constant decrease with increasing frequency for different samples, in a behavior similar to that exhibited by most semiconducting materials for samples powder ZnGeO₃. The increase of mol% PbO leads to increase the values of dielectric constant with increasing frequency (1-20) KHz. The presence of GeO₂ and PbO together with ZnO leading to decrease of dielectric constant with increasing frequency (1-20) KHz. This observation may be attributed to a combined contribution to the dielectric constant due to electric, ionic, interfacial polarization at low frequencies. At higher frequency, charge species present in the material become mobile and play a predominant role in the conduction process due to decrease in the resistive properties revealed by the resistivity spectrum results. This is due to the presence of space charge polarization.

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